

Estimating Scatterer Positions using Sparse Approximation

J. Wingses, T. Rylander

Department of Signals and systems, Chalmers University of Technology, SE-41296 Göteborg
wingses@chalmers.se

I. INTRODUCTION

We present a convex optimization method for a class of inverse scattering problems. The method is based on three steps: (i) compute a database of scattering data for the measurement situations of interest; (ii) find a sparse approximation of a measured response in terms of the database; and (iii) estimate a representative description from the sparse approximation as a weighted average.

Here, we intend to estimate the position of multiple scatterers inside the microwave measurement system shown in Fig. 1, where we measure the 6-by-6 scattering matrix in the frequency band from 2.7 GHz to 4.2 GHz. The size and

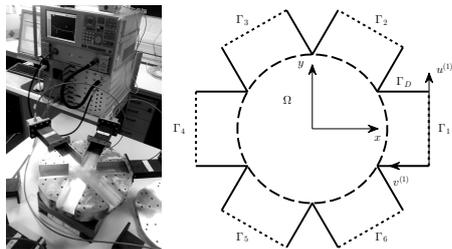


Fig. 1: To the left, partially disassembled measurement system. To the right, 2D model of the measurement region.

permittivity of the scatterers is a priori known, i.e. cylindrical acrylic-glass samples with $r = 0.52$ cm and $\epsilon_r \approx 2.54$ [1]. A 2D FEM model of the electromagnetic field problem is used to compute the scattering matrix.

First, we compute the databases \mathbf{D}_1 and \mathbf{D}_2 of the scattering data from (i) a single scatterer and (ii) two closely spaced scatterers. Here, we use 50 frequency points that are vectorized and stored in columns of \mathbf{D} . \mathbf{D}_1 and \mathbf{D}_2 are constructed for 2379 and 26171 different positions, which corresponds to a resolution of 2.1 mm and 5.3 mm, respectively. We also form $\mathbf{D}_{1\&2} = [\mathbf{D}_1, \mathbf{D}_2]$. The positions are described by the parameters \mathbf{p}_n and the scattering data is found by subtracting an empty reference case from the scattering matrix.

Next, we find the sparse approximation \mathbf{x} [2], with weights $x_n \in [0, 1]$, by solving the convex minimization problem

$$\min_{\tilde{\mathbf{x}}} \frac{1}{2} \|\tilde{\mathbf{D}}\tilde{\mathbf{x}} - \mathbf{m}\|_2^2 + \gamma \|\tilde{\mathbf{x}}\|_1, \quad (1a)$$

$$\text{s.t. } \tilde{x}_n \in [0, \|\mathbf{D}(:, n)\|_2] \quad \forall n. \quad (1b)$$

Here, \mathbf{m} is the measured scattering data and $\tilde{\mathbf{D}}(:, n) = \mathbf{D}(:, n) / \|\mathbf{D}(:, n)\|_2$. Hence, \mathbf{x} is given by $x_n = \tilde{x}_n / \|\mathbf{D}(:, n)\|_2$ and it describes a sparse linear combination of situations in \mathbf{D} , which approximates \mathbf{m} .

Finally, we estimate the scatterer positions of \mathbf{m} by combining x_n and \mathbf{p}_n as a weighted average $\hat{\mathbf{p}} \simeq \sum_n x_n \mathbf{p}_n / \sum_n x_n$, where the average is computed only for neighboring \mathbf{p}_n .

II. RESULTS

We solve (1) using either the database \mathbf{D}_1 or $\mathbf{D}_{1\&2}$ for three measurement cases with 2 samples. Here, we find that $\gamma =$

0.1 offers a good trade-off between residual and sparsity. The found non-zero x_n for each case is shown using dots at the positions \mathbf{p}_n in Fig. 2, and the gray scale indicates the weight. For most cases, we find that there are a few non-zero elements

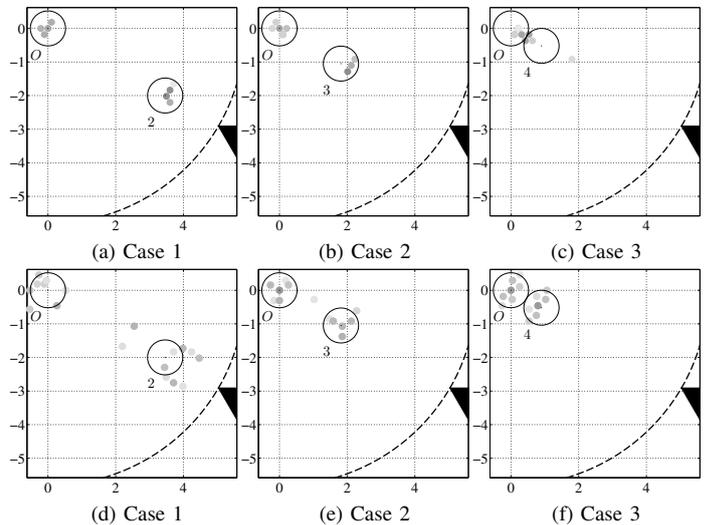


Fig. 2: Part of the measurement region with the two acrylic-glass cylinders shown by a solid circle for three different cases. In (a-c) we use \mathbf{D}_1 , and in (d-f) we use $\mathbf{D}_{1\&2}$.

in \mathbf{x} that can be associated with a single scatterer and, thereby, grouped by means of $\hat{\mathbf{p}}$. This gives the sample positions to an accuracy of 1 mm. Difficulties arise if we use (i) \mathbf{D}_1 and the two samples are close, or (ii) $\mathbf{D}_{1\&2}$ and the samples are further apart than the separation distance in \mathbf{D}_2 . Both of these difficulties are addressed by using the appropriate database.

III. CONCLUSIONS

A convex optimization method for estimating multiple scatterer positions is presented and tested in a microwave measurement system.

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